

## **The Art of Higher-Order Probe Correction in Spherical Near-Field Antenna Measurements**

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### **Abstract**

The traditional spherical near-field antenna measurement technique requires a first-order probe, i.e., a probe with only first-order azimuthal modes in the spherical wave expansion of the probe field, since this provides an efficient and robust probe-correction in the near-field to far-field transformation. This traditional technique yields high accuracy and it has matured into a well-established and widely recognized technique that forms the basis for many existing antenna measurement facilities. However, the first-order requirements significantly limit the types of antennas that can be used as probes for spherical near-field measurements; one of a very few high-accuracy, practical probes being the conical horn fed through a circular waveguide operating in the fundamental TE<sub>11</sub>-mode. This antenna has certain disadvantages since it provides only a 10-15% bandwidth and becomes unmanageable large and heavy at frequencies below 1 GHz. In recent years, a number of spherical near-field antenna measurement techniques facilitating higher-order probe correction have been proposed by several authors and these allow a wide range of probe antennas. These techniques are based on widely different approaches and may thus possess different regions of validity as well as different advantages and disadvantages. In this work, these proposed higher-order probe correction techniques are compared and evaluated wrt. to the parameters of importance for practical spherical near-field antenna measurements.